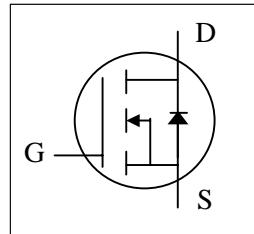
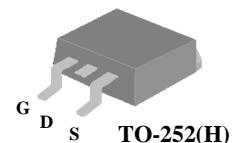




- ▼ Simple Drive Requirement
- ▼ Ultra-low On-resistance
- ▼ Fast Switching Characteristic
- ▼ RoHS Compliant & Halogen-Free



BV_{DSS}	40V
$R_{DS(ON)}$	3.6mΩ



Description

AP4N3R6 series are from Advanced Power innovative design and silicon process technology to achieve the lowest possible on-resistance and fast switching performance. It provides the designer with an extreme efficient device for use in a wide range of power applications.

TO-252 package is widely preferred for all commercial-industrial surface mount applications using infrared reflow technique and suited for high current application due to the low connection resistance.

Absolute Maximum Ratings@ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Rating	Units
V_{DS}	Drain-Source Voltage	40	V
V_{GS}	Gate-Source Voltage	+20	V
$I_D @ T_C = 25^\circ\text{C}$	Drain Current, $V_{GS} @ 10\text{V}^4$ (Silicon Limited)	130	A
$I_D @ T_C = 25^\circ\text{C}$	Drain Current, $V_{GS} @ 10\text{V}^4$	75	A
I_{DM}	Pulsed Drain Current ¹	300	A
$P_D @ T_C = 25^\circ\text{C}$	Total Power Dissipation	104	W
$P_D @ T_A = 25^\circ\text{C}$	Total Power Dissipation ⁵	2	W
E_{AS}	Single Pulse Avalanche Energy ³	45	mJ
T_{STG}	Storage Temperature Range	-55 to 150	°C
T_J	Operating Junction Temperature Range	-55 to 150	°C

Thermal Data

Symbol	Parameter	Value	Units
R_{thj-c}	Maximum Thermal Resistance, Junction-case	1.2	°C/W
R_{thj-a}	Maximum Thermal Resistance, Junction-ambient (PCB mount) ⁵	62.5	°C/W



AP4N3R6H

Electrical Characteristics@ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}$, $I_{\text{D}}=250\mu\text{A}$	40	-	-	V
$R_{\text{DS}(\text{ON})}$	Static Drain-Source On-Resistance ²	$V_{\text{GS}}=10\text{V}$, $I_{\text{D}}=40\text{A}$	-	-	3.6	$\text{m}\Omega$
		$V_{\text{GS}}=4.5\text{V}$, $I_{\text{D}}=30\text{A}$	-	-	5	$\text{m}\Omega$
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}$, $I_{\text{D}}=250\mu\text{A}$	1	-	3	V
g_{fs}	Forward Transconductance	$V_{\text{DS}}=5\text{V}$, $I_{\text{D}}=40\text{A}$	-	180	-	S
I_{DSS}	Drain-Source Leakage Current	$V_{\text{DS}}=32\text{V}$, $V_{\text{GS}}=0\text{V}$	-	-	10	uA
I_{GSS}	Gate-Source Leakage	$V_{\text{GS}}= \pm 20\text{V}$, $V_{\text{DS}}=0\text{V}$	-	-	± 100	nA
Q_{g}	Total Gate Charge	$I_{\text{D}}=40\text{A}$	-	121	194	nC
Q_{gs}	Gate-Source Charge	$V_{\text{DS}}=32\text{V}$	-	15	-	nC
Q_{gd}	Gate-Drain ("Miller") Charge		-	31	-	nC
$t_{\text{d}(\text{on})}$	Turn-on Delay Time	$V_{\text{DS}}=20\text{V}$	-	13	-	ns
t_{r}	Rise Time	$I_{\text{D}}=40\text{A}$	-	63	-	ns
$t_{\text{d}(\text{off})}$	Turn-off Delay Time	$R_{\text{G}}=3.3\Omega$	-	72	-	ns
t_{f}	Fall Time	$V_{\text{GS}}=10\text{V}$	-	110	-	ns
C_{iss}	Input Capacitance	$V_{\text{GS}}=0\text{V}$	-	6000	9600	pF
C_{oss}	Output Capacitance	$V_{\text{DS}}=20\text{V}$	-	760	-	pF
C_{rss}	Reverse Transfer Capacitance		-	330	-	pF
R_{g}	Gate Resistance	$f=1.0\text{MHz}$	-	1	2	Ω

Source-Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
V_{SD}	Forward On Voltage ²	$I_{\text{S}}=40\text{A}$, $V_{\text{GS}}=0\text{V}$	-	-	1.2	V
t_{rr}	Reverse Recovery Time	$I_{\text{S}}=40\text{A}$, $V_{\text{GS}}=0\text{V}$	-	19	-	ns
Q_{rr}	Reverse Recovery Charge	$dI/dt=100\text{A}/\mu\text{s}$	-	8	-	nC

Notes:

- 1.Pulse width limited by Max. junction temperature.
- 2.Pulse test
- 3.Starting $T_j=25^\circ\text{C}$, $V_{\text{DD}}=25\text{V}$, $L=0.1\text{mH}$, $R_{\text{G}}=25\Omega$
- 4.Package limitation current is 75A .
- 5.Surface mounted on 1 in² copper pad of FR4 board

THIS PRODUCT IS SENSITIVE TO ELECTROSTATIC DISCHARGE, PLEASE HANDLE WITH CAUTION.

USE OF THIS PRODUCT AS A CRITICAL COMPONENT IN LIFE SUPPORT OR OTHER SIMILAR SYSTEMS IS NOT AUTHORIZED.

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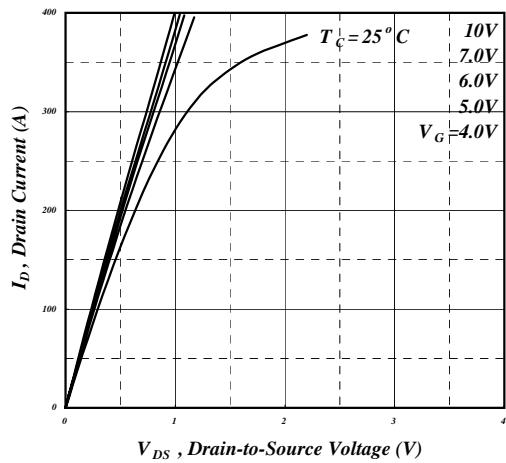


Fig 1. Typical Output Characteristics

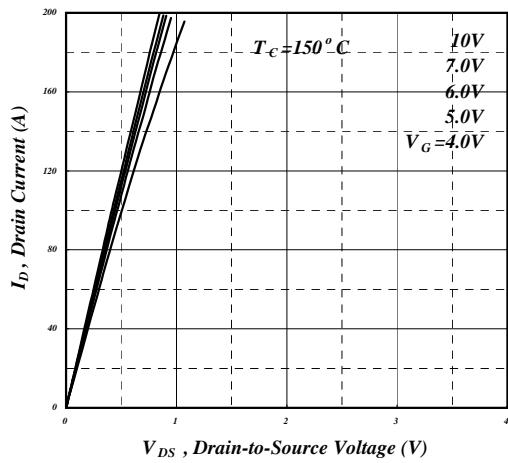


Fig 2. Typical Output Characteristics

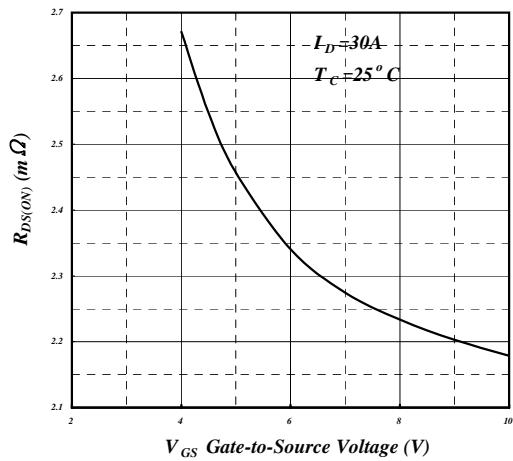


Fig 3. On-Resistance v.s. Gate Voltage

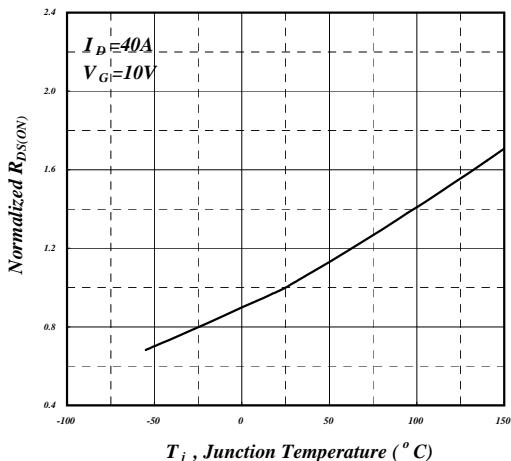


Fig 4. Normalized On-Resistance v.s. Junction Temperature

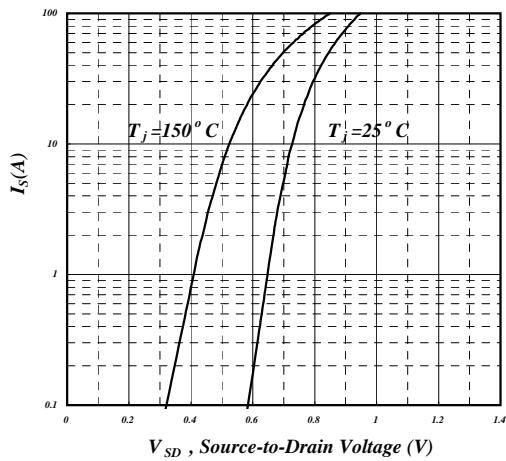


Fig 5. Forward Characteristic of Reverse Diode

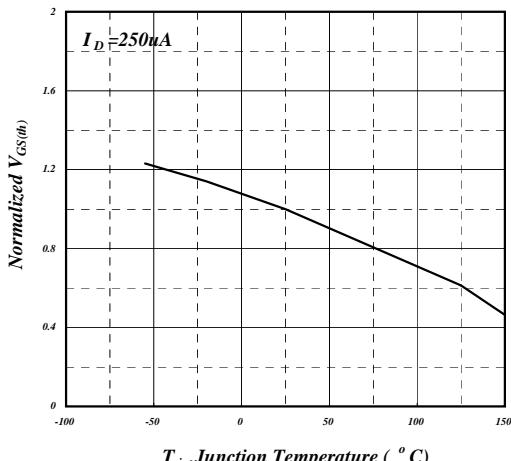


Fig 6. Gate Threshold Voltage v.s. Junction Temperature

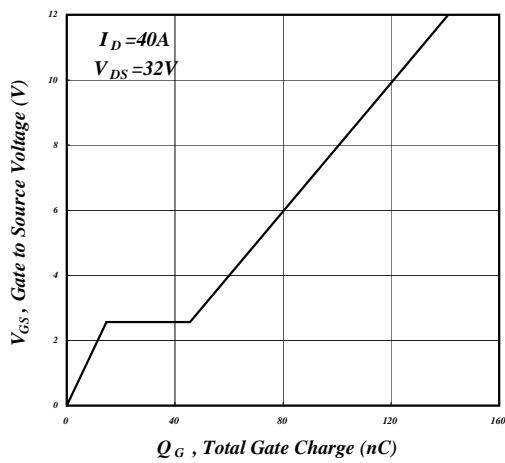


Fig 7. Gate Charge Characteristics

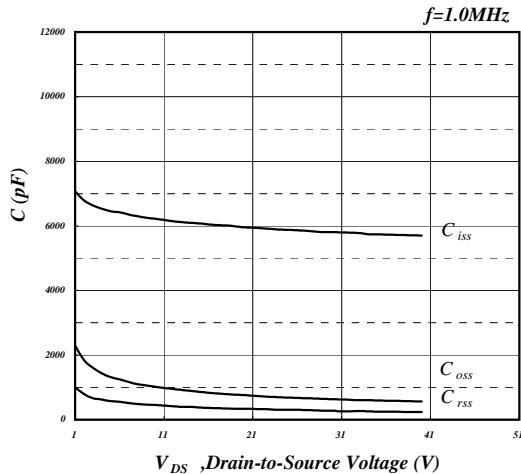


Fig 8. Typical Capacitance Characteristics

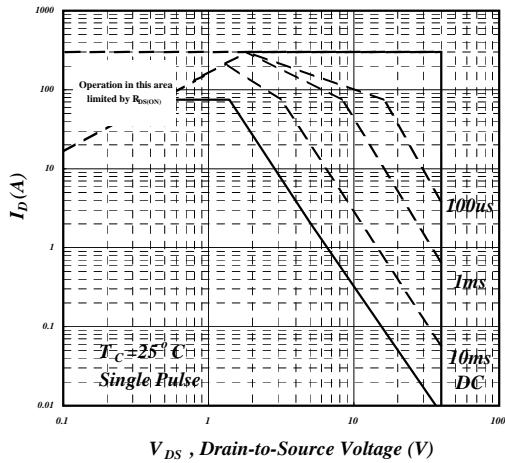


Fig 9. Maximum Safe Operating Area

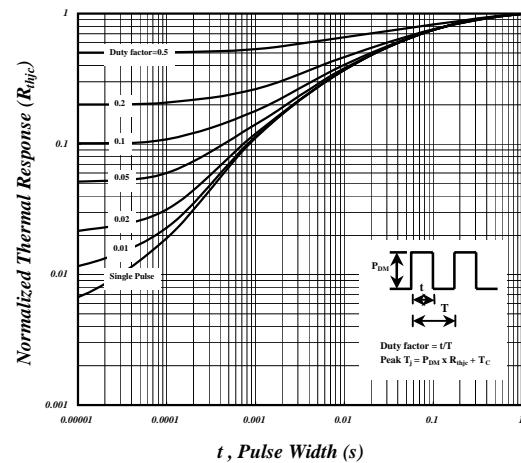


Fig 10. Effective Transient Thermal Impedance

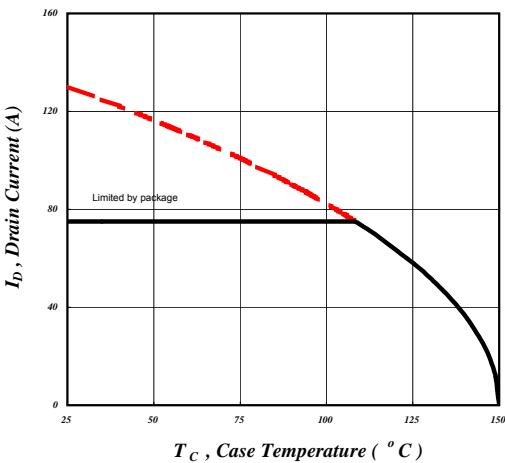


Fig 11. Drain Current v.s. Case Temperature

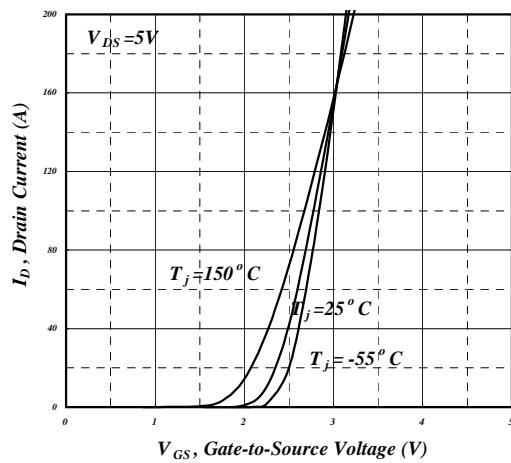


Fig 12. Transfer Characteristics

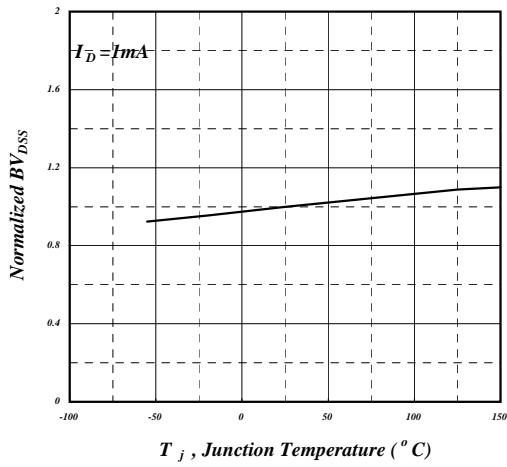


Fig 13. Normalized BV_{DSS} v.s. Junction

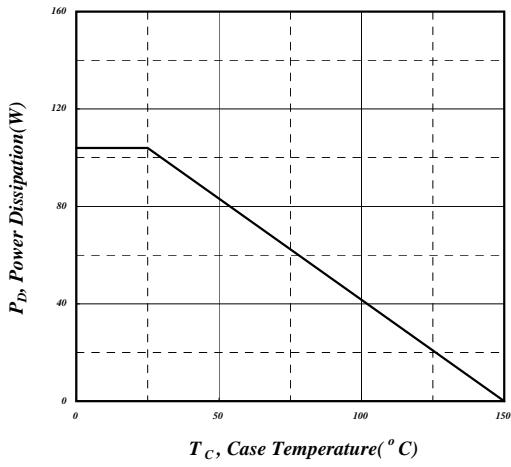


Fig 14. Total Power Dissipation

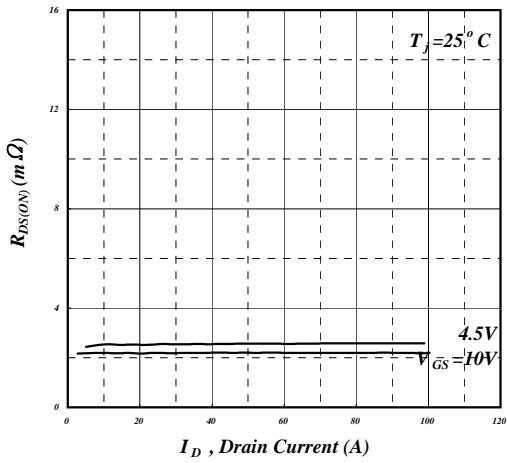


Fig 15. Typ. Drain-Source on State
Resistance



AP4N3R6H

MARKING INFORMATION

